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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/539,662	OGAWA ET AL.	
Examiner	Art Unit	
Diane Yabut	3734	

	SEARCHED				
Class	Subclass	Date	Examiner		
623	23.72	11/17/2006	DY		
606	108	11/17/2006	DY		
606	151	11/17/2006	DY		

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		
	DATE	EXMR
EAST Search see attached Search History	11/17/2006	DY
Consulted primary Julian Woo on class/subclass search	11/17/2006	DY